

Special Issue on X-Ray Diffraction

Call for Papers

X-Ray Diffraction is one of the most important characterization tools used in solid state chemistry and materials science. It relies on the dual wave/particle nature of X-rays to obtain information about the crystalline materials, such as structures, phases, preferred crystal orientations, and other structural parameters including average grain size, crystallinity, strain, and crystal defects. We can determine the size and the shape of the unit cell for any compound and biological molecule most easily using X-ray diffraction. This special issue will be focused on studying different kinds of **X-ray diffraction** and their applications.

In this special issue, we intend to invite front-line researchers and authors to submit original research and review articles on exploring **X-ray diffraction**. Potential topics include, but are not limited to:

- Single crystal diffraction
- Powder X-ray diffraction
- Protein crystallography
- X-ray techniques
- X-ray crystallography
- Instruments and approaches of X-ray diffraction
- Applications of X-ray diffraction

Authors should read over the journal's <u>For Authors</u> carefully before submission. Prospective authors should submit an electronic copy of their complete manuscript through the journal's <u>Paper Submission System</u>.

Please kindly notice that the "**Special Issue**" under your manuscript title is supposed to be specified and the research field "**Special Issue** - *X-Ray Diffraction*" should be chosen during your submission.

According to the following timetable:

Submission Deadline	December 24th, 2014
Publication Date	February 2015

Guest Editor:

For further questions or inquiries

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